

**Search Notes**

Application/Control No.

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Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

JI ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
252	79.3	11/1/2005	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	11/1/2005	BT